

Notice of References Cited	Application/Control No. 10/550,902	Applicant(s)/Patent Under Reexamination OHYA ET AL.	
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U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-			
	B	US-			
	C	US-			
	D	US-			
	E	US-			
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

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	N	11-012754	01-1999	Japan	Takami et al.	C23C 20/04
	O	09-278598	10-1997	Japan	Takami et al.	C30B 33/00
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NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	"Characterization of Pt Microcrystals Using High Resolution Electron Microscopy," N. J. Long et al. Ultramicroscopy 20 (1986), pages 15-20.
	V	"Shapes, multiple twins and surface structures of monodisperse FePt magnetic nanocrystals," Zu Rong Dai et al. Surface Science 505 (2002), pages 325-335.
	W	
	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.